

Photoresponse of Graphene-gated Graphene-GaSe Heterojunction Devices

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1. Device I

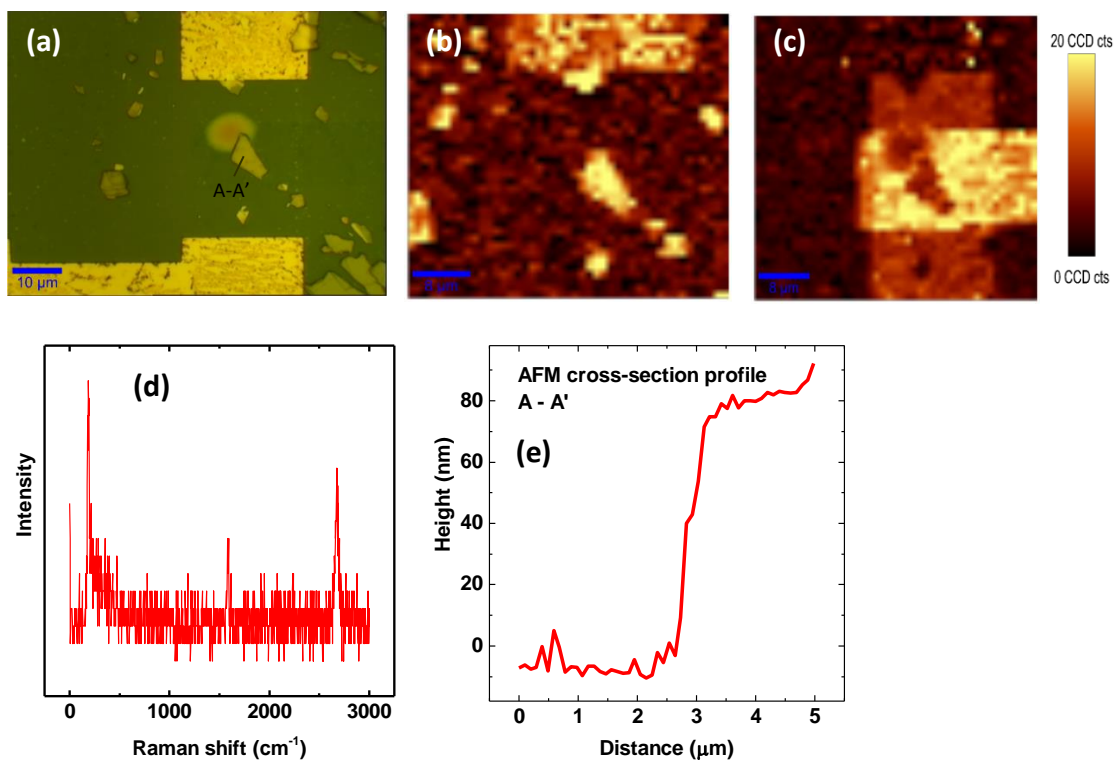
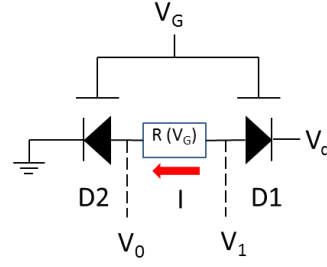
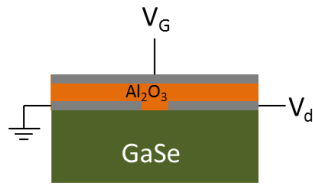


Figure S-1. Device I. (a) Optical image and Raman map for the peak of (b) GaSe appearing at $\sim 212\text{ cm}^{-1}$ (E_{12g}) and of (c) the graphene at $\sim 2680\text{ cm}^{-1}$ (2D). (d) Raman spectra corresponding to the point of the S/D area. (e) Height profile measured by AFM along the A-A' line in (a).



$T = 300 \text{ K}$
 $T_{\text{ox}} = 30 \text{ nm}$
 $\epsilon_{\text{ox}} = 8.9$
 $\epsilon_{\text{GaSe}} = 7$
 $N_a = 1e10 \text{ cm}^{-3}$
 $N_v = 2.21e17 \text{ cm}^{-3}$
 $W_g = 4.5 \text{ eV}$
 $E_{\text{gap}} = 2.1 \text{ eV}$
 $\chi_{\text{GaSe}} = 3.24 \text{ eV}$

Diode equations

$$I_2 = I_0 \exp(-\phi_{b2}/kT) \exp(qV_0/\eta_2 kT) (1 - \exp(-qV_0/kT))$$

$$I_1 = I_0 \exp(-\phi_{b1}/kT) \exp(q(V_1 - V_d)/\eta_1 kT) (1 - \exp(-q(V_1 - V_d)/kT))$$

Circuit laws

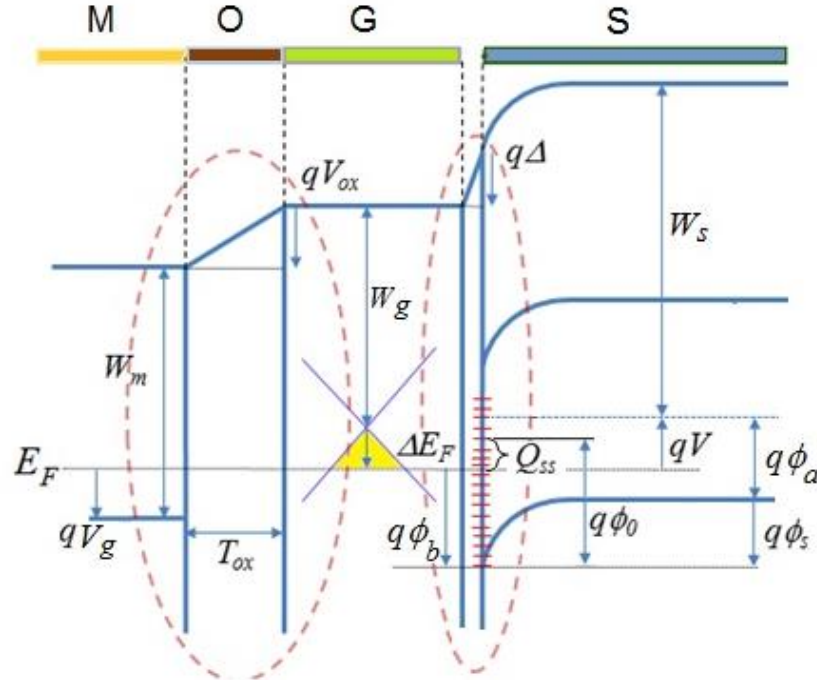
$$-I_1 = I_2 = I$$

$$V_1 - V_0 = IR$$

Remark

ϕ_{b1} and ϕ_{b2} are determined following the procedure in Refs. (24) and (35) in the main text, taking into account possible Fermi level pinning.

Band diagram of the MOGS heterostructure



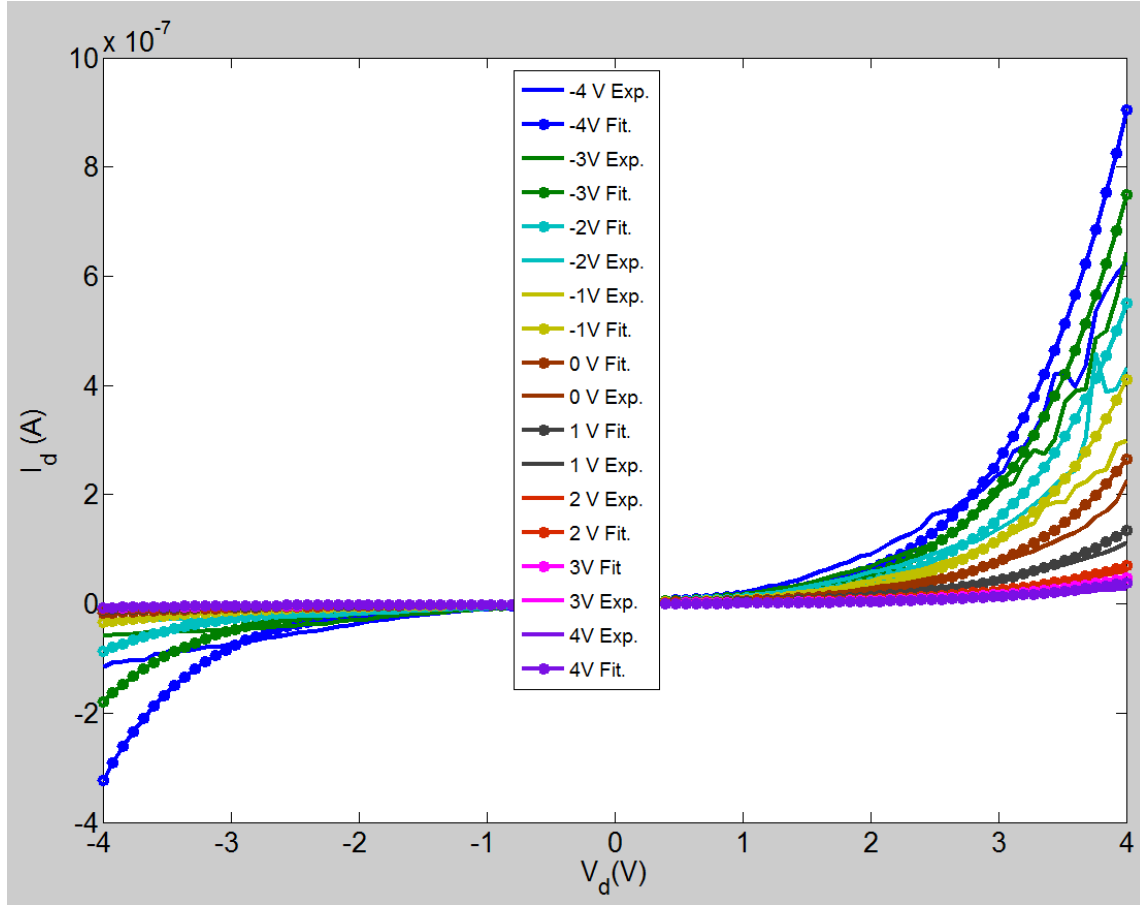


Figure S-2. Device I. Simulations for the output characteristics. (upper) Schematics of the device model and equivalent circuitries. (middle) Band diagram of the MOGS heterostructure indicating the Schottky Barrier Height ϕ_b . (lower) Simulated I-V characteristics with varied V_G in sweeping of V_D from -4 to 4 V, performed using the parameters and equations above.

2. Graphene gated metal-GaSe-metal FET

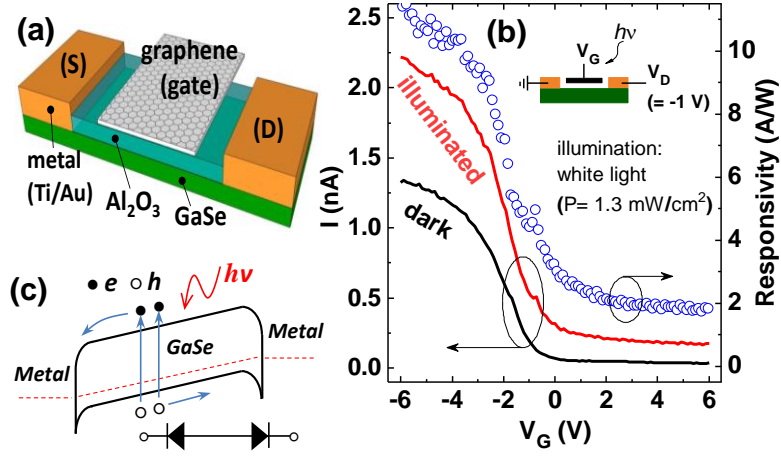


Figure S-3. (a) Schematic of graphene gated GaSe FET. (b) (left axis) Transfer characteristics of the device measured at $V_D = -1 \text{ V}$. A black and red lines denote the currents measured in dark and under illumination (white light, $P = 0.16 \text{ mW}$). (right axis) Corresponding photo-responsivity ($= I_{ph}/P_{channel}$) plotted with blue circles along V_G . The inset describes the cross-section view of device with electrical configuration. $h\nu$ is the incident light energy. (c) Band diagram describing the photocurrent generation process in hole transport when the device is biased, including equivalent circuitry (back-to-back diode configuration).

3. Device II

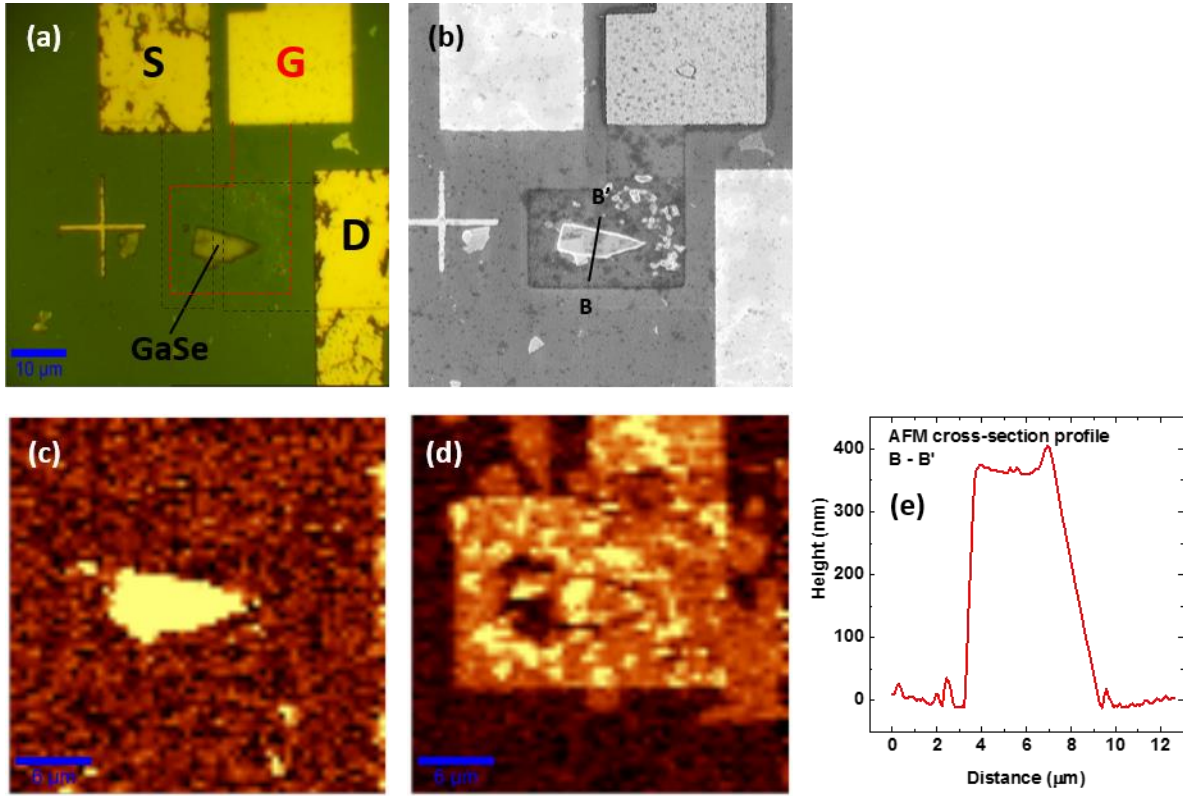


Figure S-4. Device II. (a-b) Optical and SEM image of the device. Dashed lines in black and red denote a graphene contact and a topgate, respectively. (c-d) Raman map for the peak of (c) GaSe appearing at $\sim 212 \text{ cm}^{-1}$ (E_{12g}) and (d) of the graphene at $\sim 2680 \text{ cm}^{-1}$ (2D). (e) Height profile measured by AFM along the B-B' line in (b).

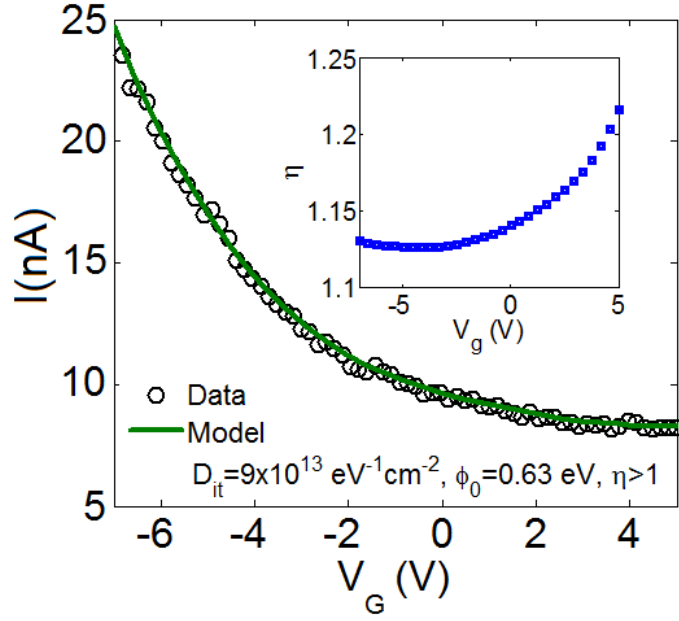


Figure S-5. Device II. Simulated transfer characteristics. The best fit to the measurements is reached when $D_{it} \sim 10^{14} \text{ eV}^{-1}\text{cm}^{-2}$ and $\phi_0 \sim E_g/3$ are assumed. To gain consistency with the experiment we have considered an ideality factor that depends on the gate bias, as shown in the inset.

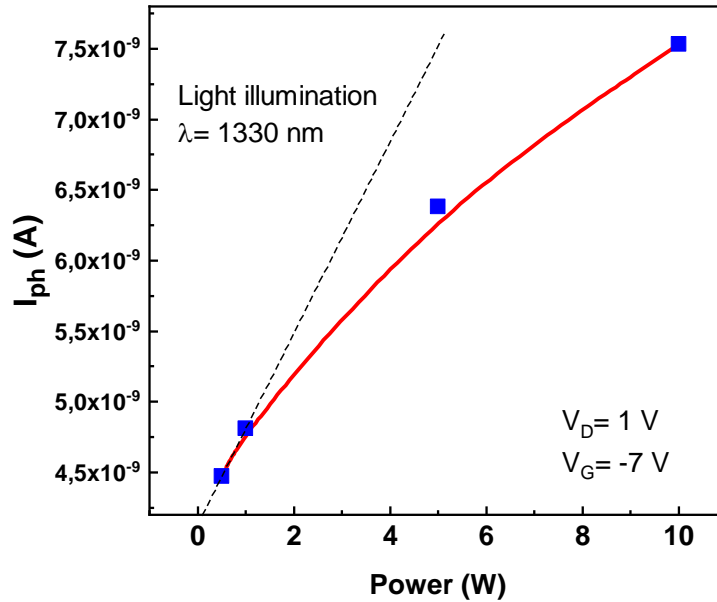


Figure S-6. Device II. Photogenerated current versus illuminated power at 1330 nm. The red line is a curve fitted to data obtained with the power (P) = 0.5, 1, 5, 10 mW. The trend of linear curve-fit to points for P = 0.5 and 1 mW is shown with a dotted line.

4. Device III

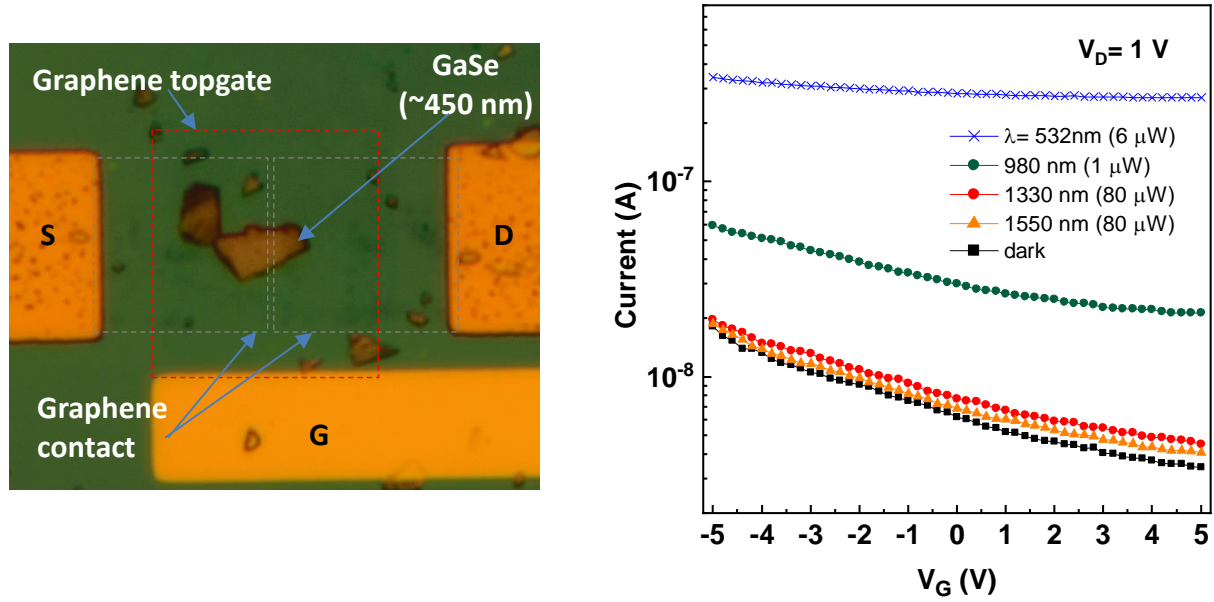


Figure S-7. Device III. (left) optical image of graphene-gated graphene-GaSe heterojunction structure. The channel size (width x length) of GaSe is $6 \times 1 \mu\text{m}^2$. (right) Transfer characteristics of the device under illumination.

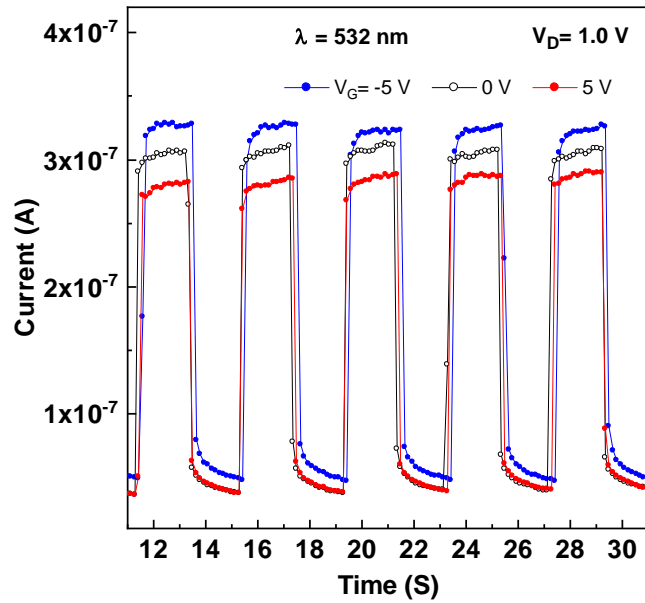


Figure S-8. Device III. Time-resolved photo-response of the device at 532 nm. Different colors denote the different gate voltages applied under illumination.

5. Graphene property

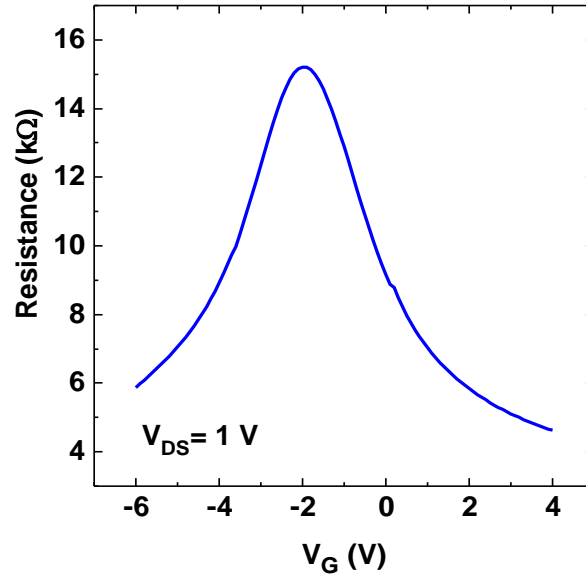


Figure S-9. Graphene FET. Total resistance versus V_G . Graphene is slightly n-type doped. The channel size of the graphene FET (width \times length) is $30 \times 30 \mu\text{m}^2$.